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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/721,512	KOBAYASHI ET AL.	
Examiner	Art Unit	
Christopher D. Biagini	2142	_

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Full-text search of US Patents, US PG-Pubs, and EPO, JPO, Derwent, and IBM-TDB databases.	1/7/2008	CDB
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